Form PTO-1449

LIST OF PATENTS AND **PUBLICATIONS** FOR INFORMATION **DISCLOSURE STATEMENT** 

APPLICANT: Frank K. Baker, Jr. et al.	
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(Use Several Sheets if Necessary)

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EXAMIN INITIA			DOCUMENT NUMBER	ISSUE DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
so.	س.	AA	5,828,603	Oct.27,'98	Pathak	365	185.21	Apr.23,'97
1		AB	5,754,817	May 19,'98	Wells et al.	395	413	Feb.12,'97
		AC	5,502,678	Mar.26,'96	McClure	365	201	Sep.30,'94
		AD	5,498,559	Mar.12,'96	Chang	437	43	Jun.20,'94
		AE	5,325,335	Jun.28,'94	Ang et al.	365	205	Jun.5,'92
		AF	4,683,554	Jul.28,'87	Lockwood et al.	365	185	Sep.13,'85
m.	W.	AG	4,316,264	Feb.16,'82	Harari	365	190	Jan.8,'80
•		AH						
-		ΑI						
		AJ						
		AK						
		AL						

## FOREIGN PATENT DOCUMENTS

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EXAMINER INITIAL		DOCUMENT NUMBER	PUBLICATION DATE (#43)	COUNTRY	CLASS	SUBCLASS
	AM					
	AN					
	AO					
	AP					
	AQ					

OTHER INFORMATION (Including Author, Title, Date, Pertinent Pages, Etc.)

M.N.	AR	Abstract, S.H. Wood et al., "Read disturb errors in a CMOS static RAM chip", 1989 IEEE Aerospace Applications Conference Digest (Cat. No.89TH0233-7), pg. 13; 1989
M.N.	AS	Abstract. T. Endoh et al., "New write/erase operation technology for flash EEPROM cells to improve the read disturb characteristics", IEICE Transactions of Electronics, Vol.E80-C, No.10, pgs.1317-1323; 10/1997.
	АТ	
	AU	
	AV	
	AW	
EXAMINER		DATE CONSIDERED 11-12-02

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